Lecture 3: Physical Optics

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- Two-Element Interferometer
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3 Ways to Understanding Optics

- Geometrical Optics: Light can be described as rays
- Physical Optics: Light can be described as waves
- Quantum Optics: Light can be described as discrete particles

Very Large Telescope Interferometer (VLTI)



Image credit: ESO

T Leporis: a Mira-like Star with the VLTI in the NIR



Image credit: ESO/J.-B. Le Bouquin et al.

Interference

Young's Double Slit Experiment



- monochromatic wave
- infinitely small (pin)holes
- source *S* generates fields $\tilde{E}(\vec{r}_1, t) \equiv \tilde{E}_1(t)$ at S_1 and $\tilde{E}(\vec{r}_2, t) \equiv \tilde{E}_2(t)$ at S_2
- two spherical waves from pinholes interfere on screen
- electrical field at *P* (without propagators *i*/λ)

$$\tilde{E}_P(t) = \tilde{E}_1(t-t_1) + \tilde{E}_2(t-t_2)$$

•
$$t_1 = r_1/c, t_2 = r_2/c$$

• *r*₁, *r*₂: path lengths from *S*₁, *S*₂ to *P*

no tilt



Change in Angle of Incoming Wave

- phase of fringe pattern changes, but not fringe spacing
- tilt of λ/d produces identical fringe pattern



Change in Wavelength

- fringe spacing changes, central fringe broadens
- integral over 0.8 to 1.2 of central wavelength
- intergral over wavelength makes fringe envelope

First Fringes from VLT Interferometer



ESO PR Photo 10a/01 (18 March 2001)

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Visibility



en.wikipedia.org/wiki/Interferometric_visibility

• "quality" of fringes described by Visibility function

$$V = \frac{I_{\rm max} - I_{\rm min}}{I_{\rm max} + I_{\rm min}}$$

*I*_{max}, *I*_{min} are maximum and adjacent minimum in fringe pattern
first introduced by Michelson

Mutual Coherence

• total field in point P (neglecting propagators)

$$\tilde{E}_{P}(t) = \tilde{E}_{1}(t-t_{1}) + \tilde{E}_{2}(t-t_{2})$$

irradiance at P, averaged over time (expectation operator E)

$$I = \mathbf{E} | ilde{E}_P(t)|^2 = \mathbf{E} \left\{ ilde{E}_P(t) ilde{E}_P^*(t)
ight\}$$

writing out all the terms

$$I = \mathbf{E} \left\{ \tilde{E}_{1}(t-t_{1})\tilde{E}_{1}^{*}(t-t_{1}) \right\} + \mathbf{E} \left\{ \tilde{E}_{2}(t-t_{2})\tilde{E}_{2}^{*}(t-t_{2}) \right\} \\ + \mathbf{E} \left\{ \tilde{E}_{1}(t-t_{1})\tilde{E}_{2}^{*}(t-t_{2}) \right\} + \mathbf{E} \left\{ \tilde{E}_{1}^{*}(t-t_{1})\tilde{E}_{2}(t-t_{2}) \right\}$$

Mutual Coherence (continued)

as before

$$I = \mathbf{E} \left\{ \tilde{E}_{1}(t-t_{1})\tilde{E}_{1}^{*}(t-t_{1}) \right\} + \mathbf{E} \left\{ \tilde{E}_{2}(t-t_{2})\tilde{E}_{2}^{*}(t-t_{2}) \right\} \\ + \mathbf{E} \left\{ \tilde{E}_{1}(t-t_{1})\tilde{E}_{2}^{*}(t-t_{2}) \right\} + \mathbf{E} \left\{ \tilde{E}_{1}^{*}(t-t_{1})\tilde{E}_{2}(t-t_{2}) \right\}$$

stationary wave field, time average independent of absolute time

$$I_{S_1} = \mathbf{E}\left\{\tilde{E}_1(t)\tilde{E}_1^*(t)\right\}, \ I_{S_2} = \mathbf{E}\left\{\tilde{E}_2(t)\tilde{E}_2^*(t)\right\}$$

irradiance at P is now

$$I = I_{S_1} + I_{S_2} + \mathbf{E} \left\{ \tilde{E}_1(t - t_1) \tilde{E}_2^*(t - t_2) \right\} + \mathbf{E} \left\{ \tilde{E}_1^*(t - t_1) \tilde{E}_2(t - t_2) \right\}$$

Mutual Coherence (continued)

as before

$$I = I_{S_1} + I_{S_2} + \mathbf{E} \left\{ \tilde{E}_1(t - t_1) \tilde{E}_2^*(t - t_2) \right\} + \mathbf{E} \left\{ \tilde{E}_1^*(t - t_1) \tilde{E}_2(t - t_2) \right\}$$

• time difference $\tau = t_2 - t_1 \Rightarrow$ last two terms become

$$\mathbf{E}\left\{\tilde{E}_{1}(t+\tau)\tilde{E}_{2}^{*}(t)\right\}+\mathbf{E}\left\{\tilde{E}_{1}^{*}(t+\tau)\tilde{E}_{2}(t)\right\}$$

equivalent to

$$2 \operatorname{Re}\left[\mathsf{E}\left\{\tilde{E}_{1}(t+\tau)\tilde{E}_{2}^{*}(t)\right\}\right]$$

o cross-term becomes 2 $\operatorname{Re}\left[\mathsf{E}\left\{\tilde{E}_{1}(t+\tau)\tilde{E}_{2}^{*}(t)\right\}\right]$

Mutual Coherence (continued)

irradiance at P

$$= I_{S_1} + I_{S_2} \\ + 2Re\left[\mathbf{E}\left\{\tilde{E}_1(t+\tau)\tilde{E}_2^*(t)\right\}\right]$$

mutual coherence function of wave field at S₁ and S₂

$$\tilde{\Gamma}_{12}(\tau) = \mathbf{E}\left\{\tilde{E}_1(t+\tau)\tilde{E}_2^*(t)\right\}$$

• therefore $I = I_{S_1} + I_{S_2} + 2 \operatorname{Re} \tilde{\Gamma}_{12}(\tau)$ • $I_1 = I_{S_1}, I_2 = I_{S_2}$: irradiances at *P* from single aperture $I = I_1 + I_2 + 2 \operatorname{Re} \tilde{\Gamma}_{12}(\tau)$

Self-Coherence

• $S_1 = S_2 \Rightarrow$ mutual coherence function = autocorrelation

$$\widetilde{\Gamma}_{11}(\tau) = \widetilde{R}_{1}(\tau) = \mathbf{E}\left\{\widetilde{E}_{1}(t+\tau)\widetilde{E}_{1}^{*}(t)\right\}$$
$$\widetilde{\Gamma}_{22}(\tau) = \widetilde{R}_{2}(\tau) = \mathbf{E}\left\{\widetilde{E}_{2}(t+\tau)\widetilde{E}_{2}^{*}(t)\right\}$$

autocorrelation functions are also called *self-coherence functions*for τ = 0

$$I_{S_1} = \mathbf{E} \left\{ \tilde{E}_1(t) \tilde{E}_1^*(t) \right\} = \Gamma_{11}(0) = \mathbf{E} \left\{ |\tilde{E}_1(t)|^2 \right\}$$
$$I_{S_2} = \mathbf{E} \left\{ \tilde{E}_2(t) \tilde{E}_2^*(t) \right\} = \Gamma_{22}(0) = \mathbf{E} \left\{ |\tilde{E}_2(t)|^2 \right\}$$

autocorrelation function with zero lag (τ = 0) represent (average) irradiance (power) of wave field at S₁, S₂

Complex Degree of Coherence

 normalized mutual coherence defines the complex degree of coherence

$$\tilde{\gamma}_{12}(\tau) \equiv \frac{\tilde{\Gamma}_{12}(\tau)}{\sqrt{\Gamma_{11}(0)\Gamma_{22}(0)}} = \frac{\mathbf{E}\left\{\tilde{E}_{1}(t+\tau)\tilde{E}_{2}^{*}(t)\right\}}{\sqrt{\mathbf{E}\left\{|\tilde{E}_{1}(t)|^{2}\right\}\mathbf{E}\left\{|\tilde{E}_{2}(t)|^{2}\right\}}}$$

• irradiance in point *P* as general interference law for a partially coherent radiation field

$$I = I_1 + I_2 + 2\sqrt{I_1I_2} Re \tilde{\gamma}_{12}(\tau)$$

Spatial and Temporal Coherence

complex degree of coherence

$$\tilde{\gamma}_{12}(\tau) \equiv \frac{\tilde{\Gamma}_{12}(\tau)}{\sqrt{\Gamma_{11}(0)\Gamma_{22}(0)}} = \frac{\mathbf{E}\left\{\tilde{E}_{1}(t+\tau)\tilde{E}_{2}^{*}(t)\right\}}{\sqrt{\mathbf{E}\left\{|\tilde{E}_{1}(t)|^{2}\right\}\mathbf{E}\left\{|\tilde{E}_{2}(t)|^{2}\right\}}}$$

measures both

- spatial coherence at S₁ and S₂
- temporal coherence through time lag au
- $\tilde{\gamma}_{12}(\tau)$ is a complex variable and can be written as:

$$\tilde{\gamma}_{12}(\tau) = |\tilde{\gamma}_{12}(\tau)| \boldsymbol{e}^{i\psi_{12}(\tau)}$$

- 0 $\leq | ilde{\gamma}_{12}(au)| \leq 1$
- phase angle $\psi_{12}(\tau)$ relates to
 - phase angle between fields at S₁ and S₂
 - phase angle difference in P resulting in time lag au

Fringes in Fiber-fed High-Resolution Spectrograph

Single order flux



Figure 7 from Rains et al. 2016, SPIE 9908, 990876

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Detector Fringes in HyViSi Detector



Coherence of Quasi-Monochromatic Light

• quasi-monochromatic light, mean wavelength $\overline{\lambda}$, frequency $\overline{\nu}$, phase difference ϕ due to optical path difference:

$$\phi = \frac{2\pi}{\overline{\lambda}}(r_2 - r_1) = \frac{2\pi}{\overline{\lambda}}c(t_2 - t_1) = 2\pi\overline{\nu}\tau$$

• with phase angle $\alpha_{12}(\tau)$ between fields at pinholes S_1 , S_2

$$\psi_{12}(\tau) = \alpha_{12}(\tau) - \phi$$

and

$${\it Re}\, ilde{\gamma}_{12}(au)\,=\,| ilde{\gamma}_{12}(au)|\cos\left[lpha_{12}(au)-\phi
ight]$$

intensity in P becomes

$$I = I_1 + I_2 + 2\sqrt{I_1I_2} |\tilde{\gamma}_{12}(\tau)| \cos [\alpha_{12}(\tau) - \phi]$$

Visibility of Quasi-Monochromatic, Partially Coherent Light

intensity in P

$$I = I_1 + I_2 + 2\sqrt{I_1I_2} |\tilde{\gamma}_{12}(\tau)| \cos [\alpha_{12}(\tau) - \phi]$$

- maximum, minimum I for $cos(...) = \pm 1$
- visibility V at position P

$$V = \frac{2\sqrt{I_1}\sqrt{I_2}}{I_1 + I_2} |\tilde{\gamma}_{12}(\tau)|$$

• for
$$l_1 = l_2 = l_0$$

 $l = 2l_0 \{1 + |\tilde{\gamma}_{12}(\tau)| \cos [\alpha_{12}(\tau) - \phi]\}$
 $V = |\tilde{\gamma}_{12}(\tau)|$

Interpretation of Visibility

• for $I_1 = I_2 = I_0$

$$I = 2I_0 \{1 + |\tilde{\gamma}_{12}(\tau)| \cos [\alpha_{12}(\tau) - \phi] \}$$

$$V = |\tilde{\gamma}_{12}(\tau)|$$

- modulus of complex degree of coherence = visibility of fringes
- modulus can therefore be measured
- shift in location of central fringe (no optical path length difference, φ = 0) is measure of α₁₂(τ)
- measurements of visibility and fringe position yield amplitude and phase of complex degree of coherence

Two-Element Interferometer

Fringe Pattern



• for
$$I_1 = I_2 = I_0$$

$$I = 2I_0 \{1 + |\tilde{\gamma}_{12}(\tau)| \cos [\alpha_{12}(\tau) - \phi]\} \quad V = |\tilde{\gamma}_{12}(\tau)|$$

• source S on central axis, fully coherent waves from two holes

$$I = 2I_0(1 + \cos \phi) = 4I_0 \cos^2 \frac{\phi}{2}$$

Fringe Pattern (continued)



- distance a between pinholes
- distance s to observation plane Σ_O, s ≫ a
- path difference $(r_2 r_1)$ in equation for ϕ in good approximation

$$r_2 - r_1 = a\theta = \frac{a}{s}y$$

and therefore

$$I = 4I_0 \cos^2 \frac{\pi a y}{s \overline{\lambda}}$$

Interference Fringes from Monochromatic Point Source



- irradiance as a function of the *y*-coordinate of the fringes in observation plane Σ_O
- irradiance vs. distance distribution is Point-Spread Function (PSF) of ideal two-element interferometer

Huygens-Fresnel Principle



en.wikipedia.org/wiki/File:Refraction_on_an_aperture_-_Huygens-Fresnel_principle.svg

- every unobstructed point of a wavefront at a given moment in time serves as a source of spherical, secondary waves with the same frequency as the primary wave
- the amplitude of the optical field at any point beyond is the coherent superposition of all these secondary, spherical waves

Diffraction



www.smkbud4.edu.my/Data/sites/vschool/phy/wave/diffraction.htm

- if obstructing structures are small compared to the wavelength, waves will spread out ⇒ diffraction
- really need to solve wave equation with boundary constraints \Rightarrow riguorous solution for only a few special cases
- various numerical ways to solve such problems (e.g. Rigorous Coupled Wave Analysis)
- Huygens-Fresnel is useful for most applications

Fraunhofer and Fresnel Diffraction



en.wikipedia.org/wiki/File:Fraunhofer_diffraction_pattern_image.PNG

- wave shape changes as it moves away from obstruction
- Fresnel (or near-field) diffraction close to obstruction
- Fraunhofer (or far-field) diffraction far away from obstruction
- rule of thumb: Fraunhofer diffraction for $R > a^2/\lambda$
 - a greatest width of obscuration
 - λ wavelength
 - *R* greater of distance between source/detector and obscuration

Slit Diffraction



hyperphysics.phy-astr.gsu.edu/hbase/phyopt/sinslit.html

• with E₀ the strength of each slit segment *i* at point *P* is

$$E_i(P) = rac{E_L}{r_i} \sin(k\omega - kr_i) \Delta y_i$$

- *i* segment index (1 M)
- E_L source strength per unit length
 - r_i distance between segment and point P
- Δy_i small segment of slit
 - D length of slit

Fraunhofer Diffraction at Single Slit

integrate along slit

$$E = E_L \int_{-D/2}^{D/2} \frac{\sin \omega t - kr}{r} dy$$

• express *r* as a function of *y*:

$$r = R - y\sin\theta + \frac{y^2}{2R}\cos^2\theta + \dots$$

R distance between center of slit and point P

• substituting, integrating and squaring for intensity:

$$I(\theta) = I(0) \left(\frac{\sin\beta}{\beta}\right)^2$$

• $\beta = (kD/2)\sin\theta$

Interpretation of Single Slit Diffraction



hyperphysics.phy-astr.gsu.edu/hbase/phyopt/sinslitd.html

- assume infinite distance from aperture for source and observation plane
- equivalent to plane waves coming from aperture into different directions
- first minimum when phase delay at edge is exactly one wave

Diffraction Effects in High-Resolution Spectrographs



SOLIS VSM Slit Diffraction on Grating

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Arbitrary Diffracting Aperture

 from before forgetting common phase term and 1/R amplitude drop-off

$$E(Y,Z) = \int \int_{\text{aperture}} A(y,z) e^{ik(Yy+Zz)/R} dS$$

- complex aperture function A(y, z) describing non-uniform absorption and phase delays
- finite aperture \Rightarrow change integration boundaries to infinity
- with $k_y = kY/R$ and $k_z = kZ/R$ we obtain

$$E(k_y, k_z) = \int \int_{\text{aperture}} A(y, z) e^{i(k_y y + k_z z)} dy dz$$

 field distribution in Fraunhofer diffraction pattern is Fourier transform of field distribution across aperture

Transfer Functions

Introduction

- linear black box system
- measure response to delta function input (transfer function)
- express output as convolution between input signal and transfer function

Point-Spread Function

- intensity is modulus squared of field distribution \Rightarrow point-spread function
- image of a point source: Point Spread Function (PSF)
- image of arbitrary object is a convolution of object with PSF
 i = o * s
 - i observed image
 - o true object, constant in time
 - s point spread function
 - * convolution

Optical Transfer Function

• after Fourier transformation:

$$I = O \cdot S$$

Fourier transformed

- / Fourier transform of image
- O Fourier transform of object
- S Optical Transfer Function (OTF)
- OTF is Fourier transform of PSF and vice versa

Modulation Transfer Function (MTF)

- is the absolute value of the optical transfer function
- describes the amplitude reduction of a sinusoidal source
- is the autocorrelation of the aperture function A

• OTF =
$$FT^{-1}(PSF) = FT^{-1}(|FT(A)|^2) = FT^{-1}(FT(A) \cdot FT(A)^*) = A*A$$





Finite Hole Diameter

- fringe spacing only depends on separation of holes and wavelength
- the smaller the hole, the larger the 'illuminated' area
- fringe envelope is Airy pattern (diffraction pattern of a single hole)

2-d Brightness Distribution



PSF of single circular aperture

PSF of two-element interferometer, aperture diameter d = 25 m, length of baseline vector $|\vec{s}| = 144$ m

 double beam interference fringes showing modulation effect of diffraction by aperture of a single pinhole

÷

4.00

2.56

1.44

0.64

0.16

Modulation Effect of Aperture



- typical one-dimensional cross-section through central part of interferogram
- visibilities are equal to one, because $I_{min} = 0$
- |γ˜₁₂(τ)| = 1 for all values of τ and any pair of spatial points, if and only if the radiation field is *strictly monochromatic*

Van Cittert-Zernike Theorem

The Problem



- relates brightness distribution of extended source and phase correlation between two points in radiation field
- extended source S incoherent, quasi-monochromatic
- positions P₁ and P₂ in observers plane Σ

$$\tilde{E}_1(t)\tilde{E}_2^*(t) = \mathbf{E}\{\tilde{E}_1(t)\tilde{E}_2^*(t)\} = \tilde{\Gamma}_{12}(0)$$

The Solution

- *I*(Ω) is intensity distribution of extended source as function of unit direction vector Ω as seen from observation plane Σ
- $\tilde{\Gamma}(\vec{r})$ is coherence function in Σ -plane
- vector \vec{r} represents arbitrary baseline
- van Cittert-Zernike theorem

$$ilde{\Gamma}(ec{r}) = \int \int_{\text{source}} I(ec{\Omega}) e^{rac{2\pi i ec{\Omega}.ec{r}}{\lambda}} dec{\Omega}$$
 $I(ec{\Omega}) = \lambda^{-2} \int \int_{\sum \text{-plane}} ilde{\Gamma}(ec{r}) e^{-rac{2\pi i ec{\Omega}.ec{r}}{\lambda}} dec{
ho}$

- Γ(r) and I(Ω) are linked through Fourier transform, except for scaling with wavelength λ
- "true" Fourier transform with *conjugate variables* $\vec{\Omega}$, \vec{r}/λ ,

• Fourier pair:
$$I(\vec{\Omega}) \Leftrightarrow \tilde{\Gamma}(\vec{r}/\lambda)$$